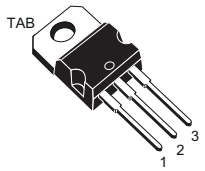
STP110N8F6

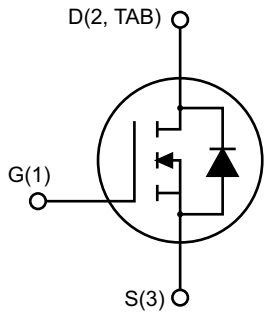
N-channel 80 V, 0.0056 Ω typ.,110 A, STripFET™ F6 Power MOSFET in a TO-220 package

Datasheet - production data



TO-220

Figure 1. Internal schematic diagram



Features

Order code	V_{DS}	$R_{DS(on)max}$	I_D	P_{TOT}
STP110N8F6	80 V	0.0065 Ω	110 A	200 W

- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using the STripFET™ F6 technology with a new trench gate structure. The resulting Power MOSFET exhibits very low $R_{DS(on)}$ in all packages.

Table 1. Device summary

Order code	Marking	Package	Packing
STP110N8F6	110N8F6	TO-220	Tube

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	80	V
V_{GS}	Gate-source voltage	±20	V
I_D	Drain current (continuous) at T_C = 25 °C	110	A
I_D	Drain current (continuous) at T_C = 100 °C	85	A
I_{DM}(1)	Drain current (pulsed)	440	A
P_{TOT}	Total dissipation at T_C = 25 °C	200	W
E_{AS}(2)	Single pulse avalanche energy	180	mJ
T_J	Operating junction temperature	-55 to 175	°C
T_{stg}	Storage temperature		°C

1. Pulse width is limited by safe operating area
2. Starting T_J = 25 °C, I_D = 55 A, V_{DD} = 60 V

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case max.	0.75	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient max.	62.5	°C/W

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4. On/off-state

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0, I_D = 1 mA	80			V
I_{DSS}	Zero-gate voltage drain current	V_{GS} = 0, V_{DS} = 80 V			1	µA
		V_{GS} = 0, V_{DS} = 80 V, T_C = 125 °C			100	µA
I_{GSS}	Gate-body leakage current	V_{DS} = 0, V_{GS} = +20 V			100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	2.5		4.5	V
$R_{DS(on)}$	Static drain-source on- resistance	V_{GS} = 10 V, I_D = 55 A		0.0056	0.0065	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 40 V, f = 1 MHz, V_{GS} = 0	-	9130	-	pF
C_{oss}	Output capacitance		-	320	-	pF
C_{rss}	Reverse transfer capacitance		-	225	-	pF
Q_g	Total gate charge	V_{DD} = 40 V, I_D = 110 A, V_{GS} = 10 V	-	150	-	nC
Q_{gs}	Gate-source charge		-	40	-	nC
Q_{gd}	Gate-drain charge		-	30	-	nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 40 V, I_D = 55 A, R_G = 4.7 Ω, V_{GS} = 10 V	-	24	-	ns
t_r	Rise time		-	61	-	ns
$t_{d(off)}$	Turn-off delay time		-	162	-	ns
t_f	Fall time		-	48	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_{SD}[(1)]	Forward on voltage	I_{SD} = 110 A, V_{GS} = 0	-		1.2	V
t_{rr}	Reverse recovery time	I_{SD} = 110 A, di/dt = 100 A/µs V_{DD} = 64 V (see)	-	30		ns
Q_{rr}	Reverse recovery charge		-	34		nC
I_{RRM}	Reverse recovery current		-	2.3		A

1. Pulsed: pulse duration = 300 µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

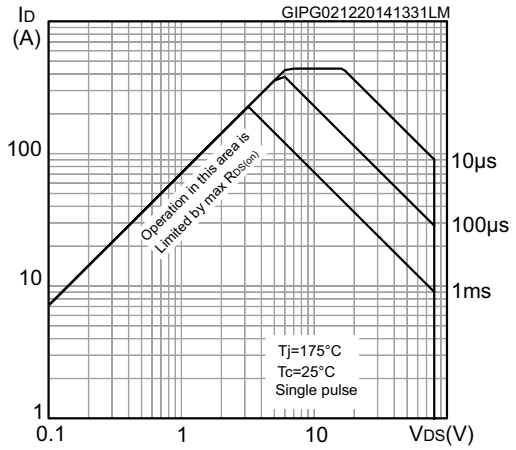


Figure 3. Thermal impedance

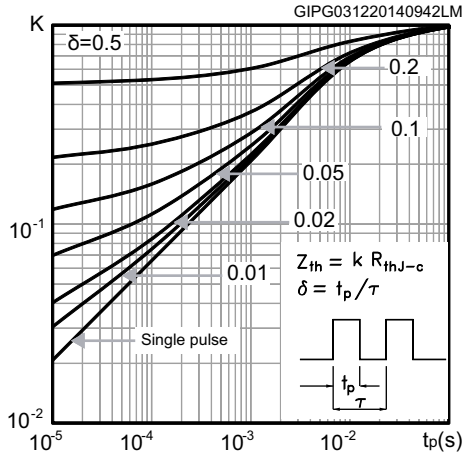


Figure 4. Output characteristics

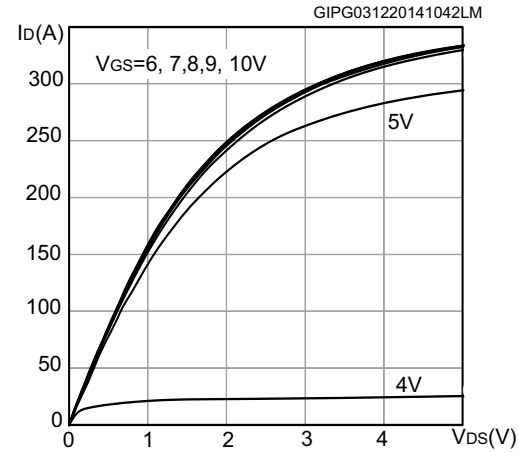


Figure 5. Transfer characteristics

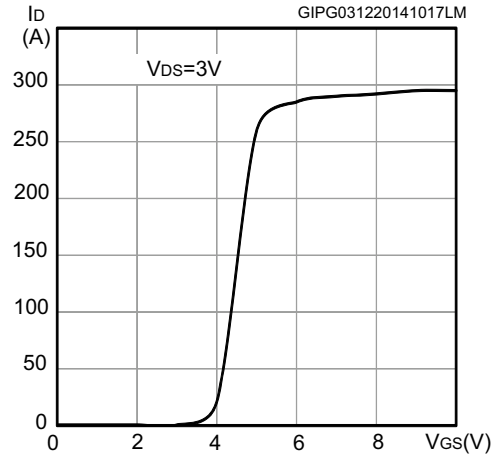


Figure 6. Gate charge vs gate-source

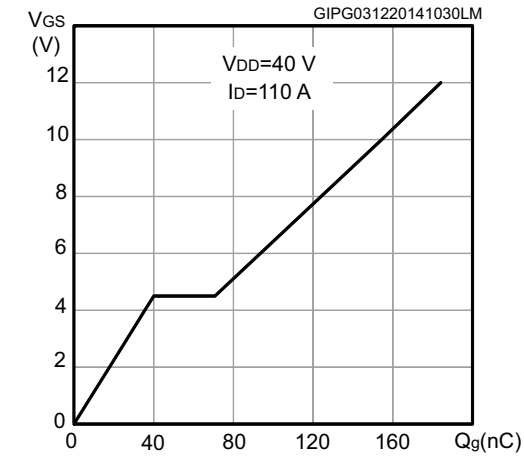


Figure 7. Static drain-source on-resistance